

ZETEX SEMICONDUCTORS

**N-Channel enhancement
mode vertical DMOS FET****ZVN3306****FEATURES**

- Compact geometry
- Fast switching speeds
- No secondary breakdown
- Excellent temperature stability
- High input impedance
- Low current drive
- Ease of paralleling

DESCRIPTION

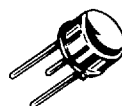
A compact interdigitated geometry forms the basis of this Zetex MOSFET. Optimised for low on-resistance, low capacitance and fast switching this device is manufactured using the latest computer controlled processing techniques in order to achieve greater stability, reliability and ruggedness.

PRODUCT SUMMARY

Part No.	BV_{DSS}	I_D	$R_{DS(on)}$
ZVN3306A	60V	0.27 A	5 Ω
ZVN3306B	60V	0.75 A	5 Ω
ZVN3306F	60V	0.15 A	5 Ω
ZVN3306E	60V	0.27 A	5 Ω



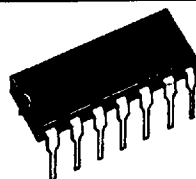
**E-LINE (TO-92)
SUFFIX A**



**TO-39
SUFFIX B**



**SOT-23
SUFFIX F**



**14 LEAD MOULDED DIL
SUFFIX E**

ZVN3306

ZETEX SEMICONDUCTORS

ABSOLUTE MAXIMUM RATINGS

Parameters		E-line	TO-39	SOT-23	DIL	Units
V_{DS}	Drain-source voltage	60	60	60	60	V
I_D	Continuous drain current (@ $T_A = 25^\circ\text{C}$)	0.27	0.27	0.15	0.27	A
I_D	Continuous drain current (@ $T_C = 25^\circ\text{C}$)	—	0.75	—	—	A
I_{DM}	Pulsed drain current	3	3	3	3	A
V_{GS}	Gate-source voltage	± 20	± 20	± 20	± 20	V
P_D	Max. power dissipation (@ $T_A = 25^\circ\text{C}$)	0.625	0.625	0.25	0.85	W
P_D	Max. power dissipation (@ $T_C = 25^\circ\text{C}$)	—	5	—	—	W
T_J, T_{stg}	Operating/storage temperature range	-55 to +150				$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS (at $T = 25^\circ\text{C}$ unless otherwise stated)

Parameter		Min.	Typ.	Max.	Unit	Conditions
BV_{DSS}	Drain-source breakdown voltage	60	—	—	V	$I_D = 1\text{mA}$, $V_{GS} = 0\text{V}$
$V_{GS(th)}$	Gate-source threshold voltage	0.8	—	2.4	V	$I_D = 1\text{mA}$, $V_{DS} = V_{GS}$
I_{GSS}	Gate body leakage	—	—	20	nA	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$
I_{DSS}	Zero gate voltage drain current	—	—	0.5	μA	$V_{DS} = \text{Max. rating}$, $V_{GS} = 0\text{V}$
		—	—	50	μA	$V_{DS} = 0.8 \times \text{Max. rating}$, $V_{GS} = 0\text{V}$ ($T = 125^\circ\text{C}$) (2)
$I_{D(on)}$	On-state drain current (1)	750	—	—	mA	$V_{DS} = 18\text{V}$, $V_{GS} = 10\text{V}$
$R_{DS(on)}$	Static drain-source on-state resistance (1)	—	—	5	Ω	$I_D = 500\text{mA}$, $V_{GS} = 10\text{V}$
g_{fs}	Forward transconductance (1) (2)	150	—	—	mS	$V_{DS} = 18\text{V}$, $I_D = 500\text{mA}$
C_{iss}	Input capacitance (2)	—	—	35	pF	$V_{DS} = 18\text{V}$, $V_{GS} = 0\text{V}$ $f = 1\text{MHz}$
C_{oss}	Common source output capacitance (2)	—	—	25	pF	
C_{rss}	Reverse transfer capacitance (2)	—	—	8	pF	
$t_{d(on)}$	Turn-on delay time (2) (3)	—	3	5	ns	$V_{DD} \approx 18\text{V}$, $I_D = 500\text{mA}$
t_r	Rise time (2) (3)	—	4	7	ns	
$t_{d(off)}$	Turn-off delay time (2) (3)	—	4	6	ns	
t_f	Fall time (2) (3)	—	5	8	ns	

SOURCE-DRAIN DIODE CHARACTERISTICS

Parameter	Typ.	Unit	Conditions	
V _{SD}	Diode forward voltage (1)	0.85	V	V _{GS} = 0V, I _S = 270mA
t _{rr}	Reverse recovery time	90	ns	V _{GS} = 0V, I _F = 270mA I _R = 100mA

(1) Measured under pulsed conditions. Width = $300\mu s$. Duty cycle $\leq 2\%$.

(2) Sample test.

(3) Switching times measured with 50Ω source impedance and $< 5ns$ rise time on a pulse generator.

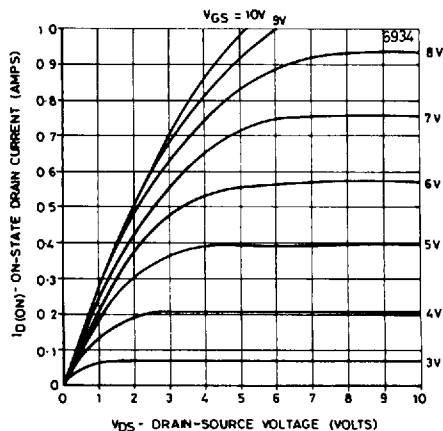


Fig. 1 Typical saturation characteristics

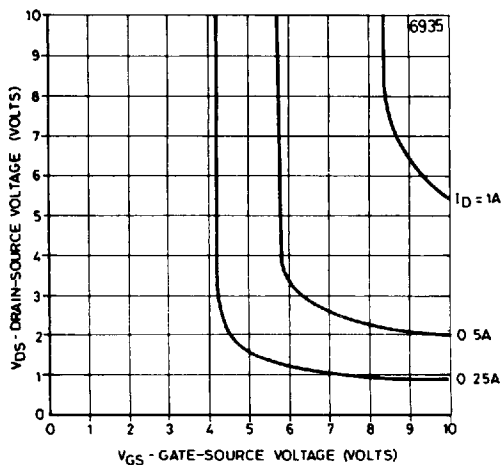


Fig. 2 Typical voltage saturation characteristics

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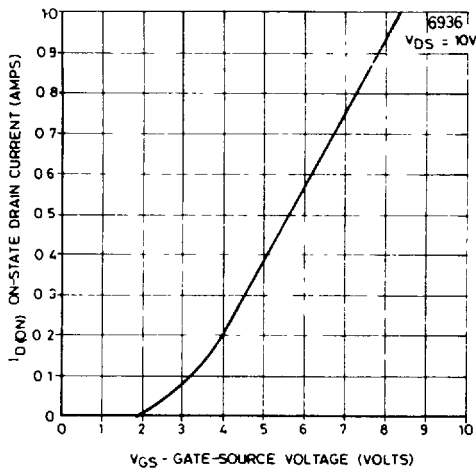


Fig. 3 Typical transfer characteristics

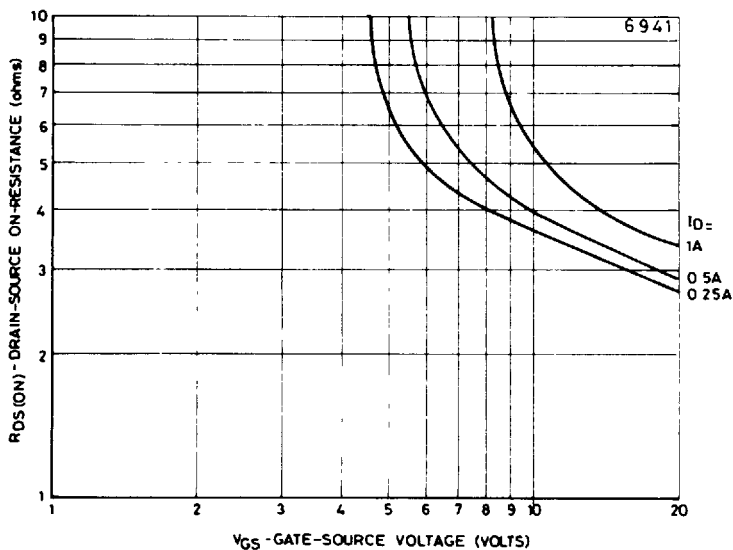


Fig. 4 Typical on-resistance v gate-source voltage

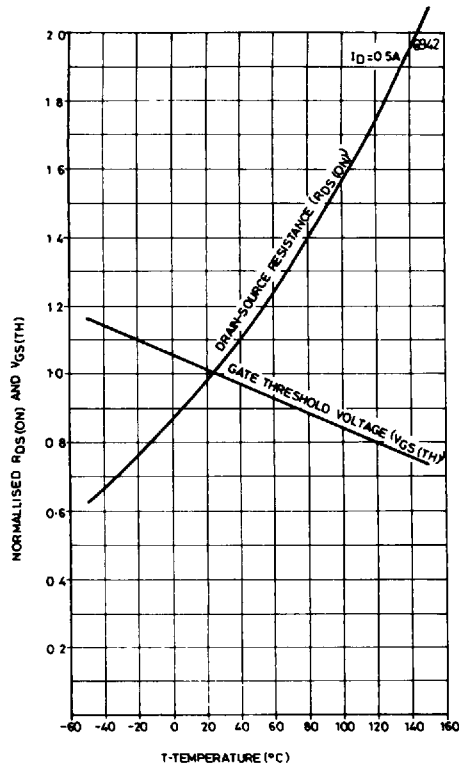


Fig. 5 Normalised $R_{DS(on)}$ and $V_{GS(th)}$ v temperature

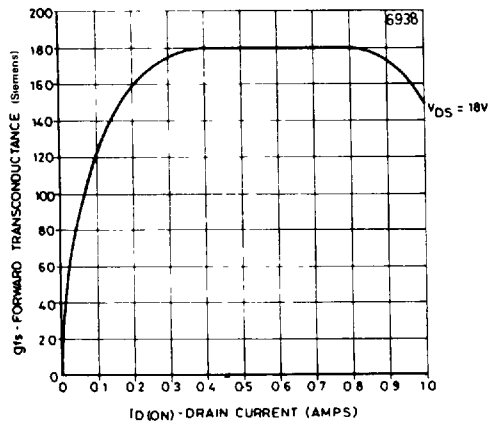


Fig. 6 Typical transconductance v drain current

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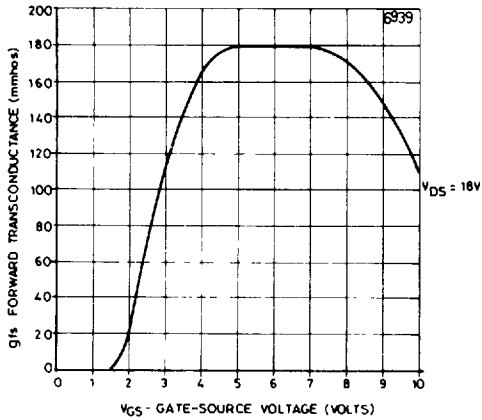


Fig. 7 Typical transconductance v gate-source voltage

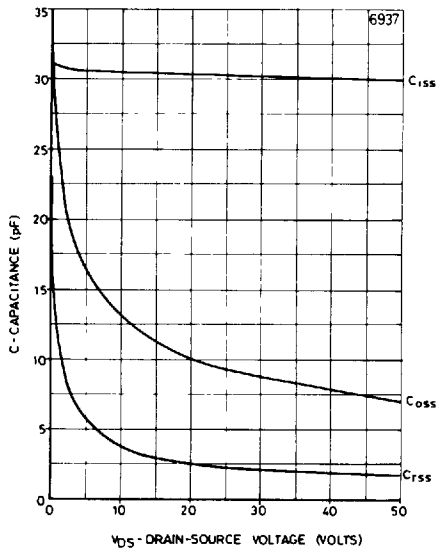


Fig. 8 Typical capacitance v drain-source voltage

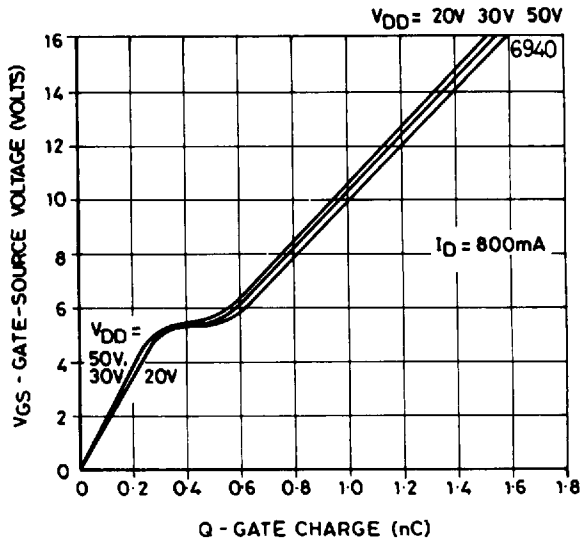


Fig. 9 Typical gate charge v gate-source voltage

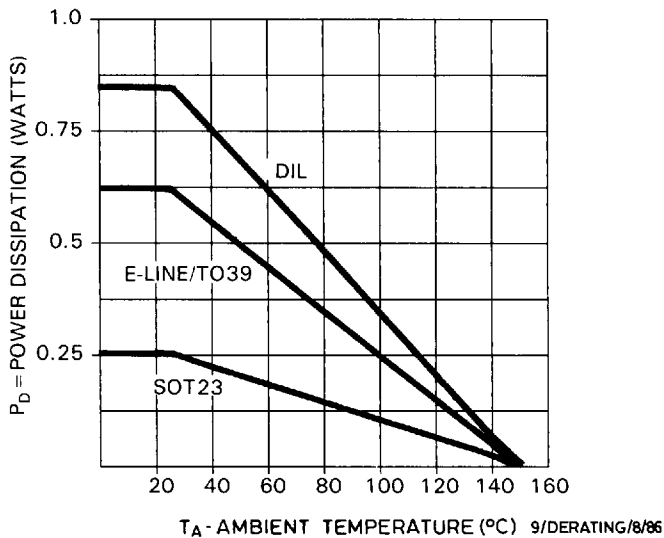
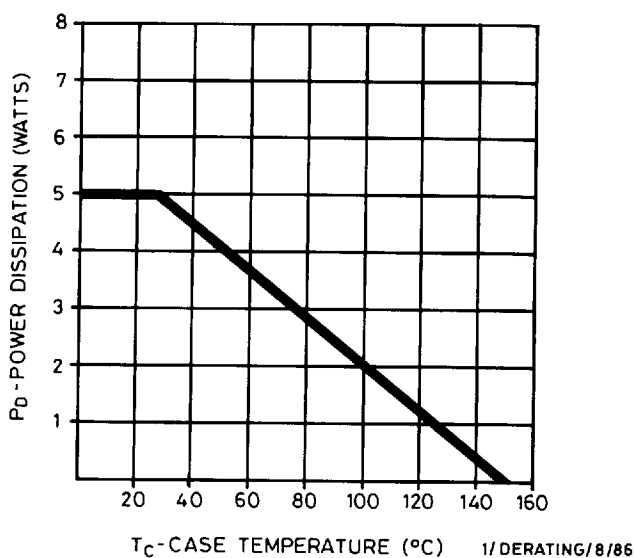


Fig. 10 Power v temperature derating curve (ambient)

ZVN3306**ZETEX SEMICONDUCTORS****Fig. 11 Power v temperature derating curve (case)**